Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/668,329	CHEN ET AL.	
Examiner	**Art Unit**	
Y. J. Han	2838	

SEARCHED			
Class	Subclass	Date	Examiner
363	19		
	45		
	81		
	84		
	86		
	125		
	126		
361	503		
	674		
	821		
73	40.5R	4/05	
search	updated	9/05	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See Search History		9/05	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR